DM74LS166 8-Bit Parallel-In/Serial-Out Shift Register

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DM74LS166 8-Bit Parallel-In/Serial-Out Shift Register

General Description

These parallel-in or serial-in, serial-out shift registers feature gated clock inputs and an overriding clear input. All inputs are buffered to lower the drive requirements to one normalized load, and input clamping diodes minimize switching transients to simplify system design. The load mode is established by the shift/load input. When HIGH, this input enables the serial data input and couples the eight flip-flops for serial shifting with each clock pulse. When LOW, the parallel (broadside) data inputs are enabled and synchronous loading occurs on the next clock pulse. During parallel loading, serial data flow is inhibited. Clocking is accomplished on the LOW-to-HIGH level edge of the clock pulse through a two-input NOR gate, permitting one input to be used as a clock-enable or clock-inhibit function. Holding either of the clock inputs HIGH inhibits clocking; holding either LOW enables the other clock input. This allows the system clock to be free running, and the register can be stopped on command with the other clock input. The clock-inhibit input should be changed to the high level only while the clock input is HIGH. A buffered, direct clear input overrides all other inputs, including the clock, and sets all flip-flops to zero.

Ordering Code:

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Order Number	Package Number	Package Description		
DM74LS166M	M16A	16-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150 Narrow		
DM74LS166WM	M16B	16-Lead Small Outline Intergrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide		
DM74LS166N	N16E	16-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide		

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code

Connection Diagram



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Function Table

Inputs					Internal		Output	
Clear	Shift/	Clock	Clock	Serial	Parallel	Outputs		Q _H
	Load	Inhibit			АН	Q _A	QB	†
L	Х	Х	Х	Х	Х	L	L	L
н	Х	L	L	Х	Х	Q _{A0}	Q _{B0}	Q _{H0}
н	L	L	Ŷ	Х	ah	а	b	h
н	н	L	Ŷ	н	Х	н	Q _{An}	Q _{Gn}
Н	н	L	Ŷ	L	Х	L	Q _{An}	Q _{Gn}
н	Х	н	Ŷ	Х	Х	Q _{A0}	Q_{B0}	Q _{H0}

H = HIGH Level (steady state) L = LOW Level (steady state)

X = Don't Care (any input, including transitions)

a...h = The level of steady-state input at inputs A through H, respectively

 $Q_{A0}, Q_{B0}, Q_{H0} =$ The level of Q_A, Q_B, Q_H , respectively, before the indicated steady-state input conditions were established

QAn, QGn, = The level of QA, QG, respectively, before the most recent 1 transition of the clock



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Absolute Maximum Ratings(Note 1)

Supply Voltage	7V
Input Voltage	7V
Operating Free Air Temperature Range	0°C to +70°C
Storage Temperature Range	-65°C to +150°C

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

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Recommended Operating Conditions

Symbol	Parameter		Min	Nom	Max	Units
V _{CC}	Supply Voltage		4.75	5	5.25	V
V _{IH}	HIGH Level Input Voltage		2			V
VIL	LOW Level Input Voltage				0.8	V
он	HIGH Level Output Current				-0.4	mA
OL	LOW Level Output Current				8	mA
CLK	Clock Frequency (Note 2) Clock Frequency (Note 3)		0		25	MHz
			0		20	MHz
t _W Pulse Width (Note 4)	Pulse Width (Note 4)	Clock	20			ns
		Clear	20			
t _{SU}	Setup Time (Note 4)	Mode	30			
	Data		20			- ns
ĥ	Hold Time (Note 4)		0			ns
Γ _A	Free Air Operating Temperature		0		70	°C

Note 2: $C_L = 15 \text{ pF}$, $R_L = 2 \text{ k}\Omega$, $T_A = 25^{\circ}\text{C}$ and $V_{CC} = 5\text{V}$.

Note 3: C_L = 50 pF, R_L = 2 k $\Omega,~T_A$ = 25°C and V_{CC} = 5V.

Note 4: T_A = 25°C and V_{CC} = 5V.

Electrical Characteristics

over recommended operating free air temperature range (unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ (Note 5)	Max	Units
VI	Input Clamp Voltage	$V_{CC} = Min, I_I = -18 mA$			-1.5	V
V _{OH}	HIGH Level Output Voltage	$V_{CC} = Min, I_{OH} = Max$ $V_{IL} = Max, V_{IH} = Min$	2.7	3.4		V
V _{OL}	LOW Level Output Voltage	$V_{CC} = Min, I_{OL} = Max$ $V_{IL} = Max, V_{IH} = Min$		0.35	0.5	v
		$I_{OL} = 4 \text{ mA}, V_{CC} = \text{Min}$		0.25	0.4	
l _l	Input Current @ Max Input Voltage	$V_{CC} = Max, V_I = 7V$			0.1	mA
IIH	HIGH Level Input Current	$V_{CC} = Max, V_I = 2.7V$			20	μΑ
I _{IL}	LOW Level Input Current	$V_{CC} = Max, V_I = 0.4V$			-0.4	mA
I _{OS}	Short Circuit Output Current	V _{CC} = Max (Note 6)	-20		-100	mA
I _{CC}	Supply Current	V _{CC} = Max (Note 7)		22	38	mA

Note 5: All typicals are at V_{CC} = 5V, T_A = 25°C.

Note 6: Not more than one output should be shorted at a time, and the duration should not exceed one second.

Note 7: With all outputs OPEN, 4.5V applied to the serial input, all other inputs except the CLOCK grounded, I_{CC} is measured after a momentary ground, then 4.5V is applied to the CLOCK.



Switching Characteristics

at $V_{CC} = 5V$ and $T_A = 25^{\circ}C$ $\mathbf{R}_{\mathbf{L}} = \mathbf{2} \mathbf{k} \Omega$ From (Input) $C_L = 15 \text{ pF}$ $C_L = 50 \ pF$ Symbol Parameter To (Output) Units Min Max Min Max Maximum Clock Frequency 25 20 MHz $\mathsf{f}_{\mathsf{MAX}}$ Propagation Delay Time t_{PLH} Clock to Output 8 35 38 ns LOW-to-HIGH Level Output Propagation Delay Time t_{PHL} Clock to Output 8 35 41 ns HIGH-to-LOW Level Output Propagation Delay Time t_{PHL} Clear to Output 30 6 36 ns HIGH-to-LOW Level Output



Test Table for Synchronous Inputs

Data Input for Test	Shift/Load	Output Tested (See Note C)		
Н	0V	Q _H at T _{N+1}		
Serial Input	4.5V	Q_H at T_{N+8}		

Note A: The clock pulse has the following characteristics: $t_{W(clock)} \ge 20$ ns and PRR = 1 MHz. The clear pulse has the following characteristics: $t_{W(clear)} \ge 20 \text{ ns and } t_{HOLD} = 0 \text{ ns. When testing } f_{MAX}, \text{ vary the clock PRR.}$ Note B: A clear pulse is applied prior to each test.

Note C: Propagation delay times (t_{PLH} and t_{PHL}) are measured at t_{n+1} . Proper shifting of data is verified at t_{n+8} with a functional test.

Note D: $t_n = bit$ time before clocking transition

 t_{n+1} = bit time after one clocking transition

 t_{n+8} = bit time after eight clocking transitions

Note E: $V_{REF} = 1.3V$.

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